PERFORMANCE CHECKSHEET

Model: AVR-EB4-B-VXI
Type: Semiconductor Device Tester
S.N.: 14050
Date: December 8, 2020

Basic specifications: →

Test Waveforms

With an On Semi 1N4937 (date code 1849) installed in the AVX-TRR-MIX test jig, connected using the 60 cm / 24" coaxial cable:

$I_F = +2A$, $I_R = -4A$, $I_{RR} = -1A$.
100 Hz, 20 us PW.
5V (1A) / div, 40 ns/div.
Measured $t_{RR} = 106$ ns.

With a generic 1N4004 installed in the AVX-TRR-MIX test jig, connected using the 60 cm / 24" coaxial cable:

$I_F = +2A$, $I_R = -4A$, $I_{RR} = -1A$.
100 Hz, 20 us PW.
5V (1A) / div, 400 ns/div.
Measured $t_{RR} = 1.10$ us.
Mainframe output, with a zero Ohm jumper installed in the AVX-TRR-MIX test jig:

50 V / div, 40 ns/div. +100V, -200V.
10% - 90% fall time shown.